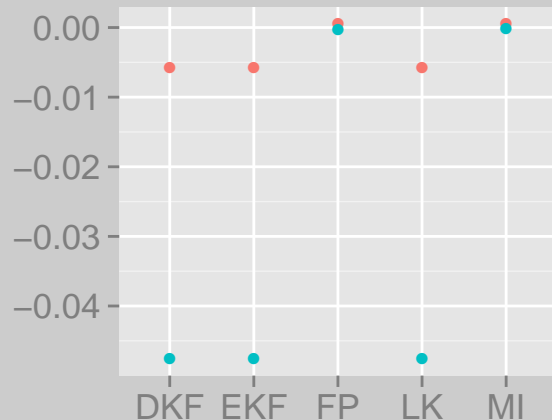
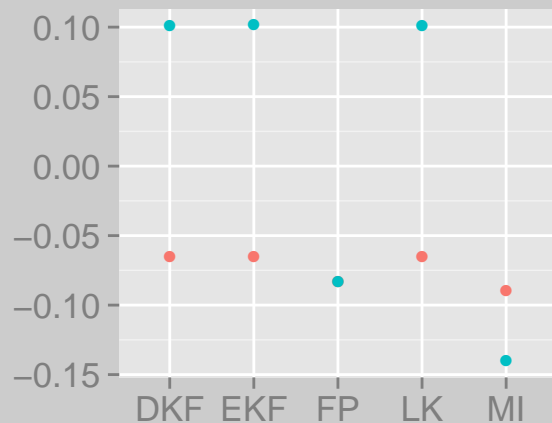


Bias

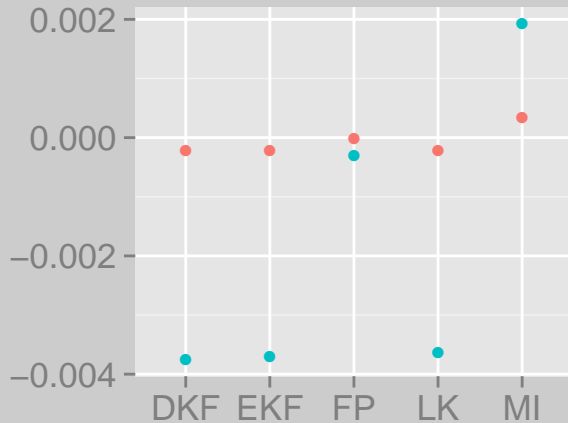
Measurement



Process Noise



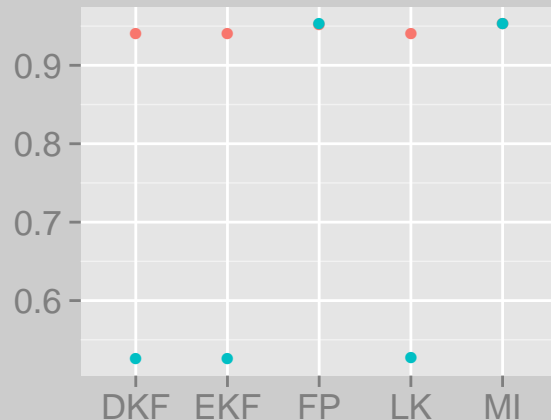
Time Series



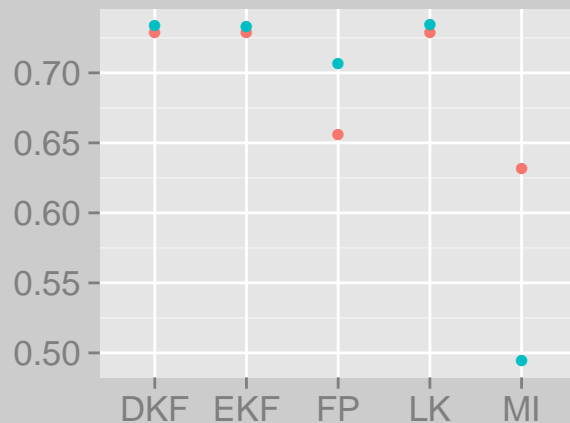
FittedIC

Coverage Rates

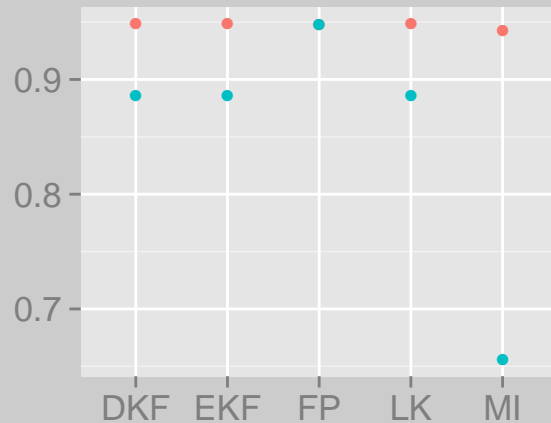
Measurement



Process Noise



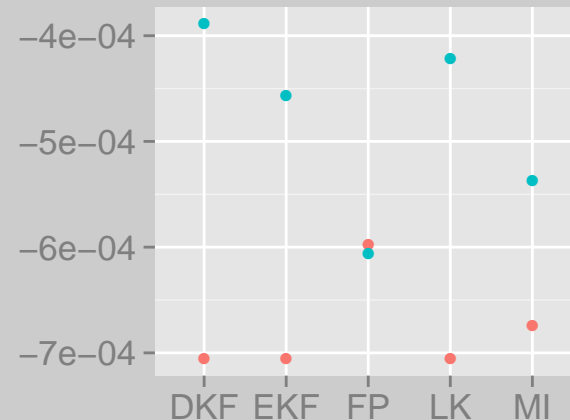
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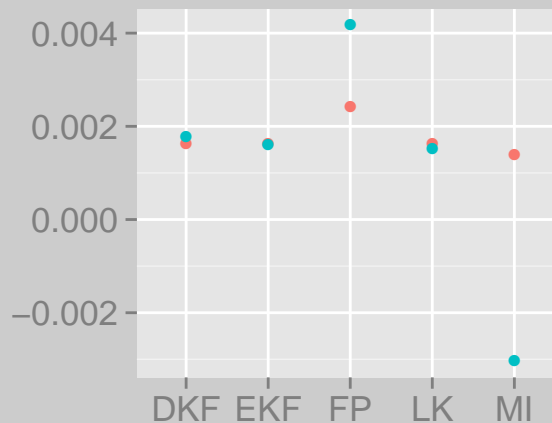
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SD - SE

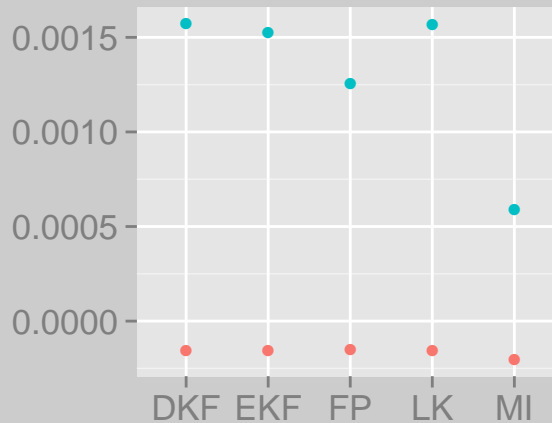
Measurement



Process Noise



Time Series



FittedIC